



ANALYTICAL INSTRUMENTS GROUP

EXPLORER



MULTI-PURPOSE AND HIGH RESOLUTION X-RAY DIFFRACTOMETER

www.gnr.it

About us

G.N.R. S.r.l., thanks to its 30 years of experience, is a worldwide market manufacturer of advanced analytical instruments, developing procedures of analysis for various applications, supplying the corresponding laboratory equipment and providing consulting and Customer support worldwide, through its well established sales and post-sale network.

G.N.R. S.r.l. projects and manufactures Optical Emission Spectrometers (OES) and Rotating Disc Electrode Optical Emission Spectrometers (RDE-OES) for the measurement of elemental composition of metal alloys and the analysis of contaminants, additives and wear metals in oils and lubricants, coolants and hydraulic fluids.

G.N.R. S.r.l. designs and produces X-Ray Diffractometers (XRD) and X-Ray Fluorescence Spectrometers (XRF) for the study of material structure and elemental composition for both academic and industrial applications.



GNR Head Office and Production Site is located in Agrate Conturbia (Novara), near Lago Maggiore; 20 minutes from MALPENSA Airport.

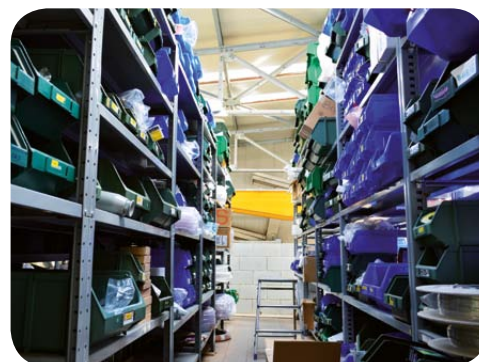
Certified Company

Highest quality in our products and services is a core value for GNR.

Full commitment is dedicated to support our quality system in the overall process and continuous improvement is fundamental to guarantee GNR compliance to the internationally accepted quality management standard ISO 9001.



GNR periodically organizes at its facility courses and training for technicians and agents as well as seminars and demonstrations.



Thanks to an extensive network of agents GNR provides technical support and delivers spare parts worldwide.

In relation to the process of continuous development, GNR reserves the right to change specifications of the instruments without previous notice at any time; the real ones will always be those shown in the final order confirmation.



GNR Analytical Instruments Group is a worldwide market leader in supplying advanced X-Ray (XRD, XRF) and Optical Emission Spectrometer (OES) systems for complete solutions in structural and elemental analysis.

These analytical methods provide elemental composition of solids and liquids as well as structural parameters of powders, thin films and bulk materials.

GNR new generation of instruments has been designed with many improved features and functionalities. GNR has completely reviewed several parts of its diffractometer system with the aim to provide the most advanced and efficient tool for customer analytical tasks.

The modularity and flexibility of **GNR Explorer** allows starting with an entry level set up system that can be upgraded in any time to meet additional requirements.

With no limits to its applications, **GNR Explorer** modular system offers high performances in all analytical areas, ranging from phase quantification of mixtures to the determination of microstructural properties as residual stress and preferred orientation of crystallites on bulk materials as well as on thin films.

Thanks to the **modularity and the Plug&Scan concept** all the components can be quickly exchanged with extremely precise reproducible positioning. The optics permit switching from parafocusing Bragg-Brentano to parallel beam geometry without any extra alignment. All optics have been designed to return to perfect alignment every time.

From the X-ray tube, through the optics, to the sample stages and to the detectors, any user is capable of changing from one beam geometry to another very easily.

GNR Explorer offers solutions for a wide range of analytical requirements, from routine crystalline phase identification and quantification, to crystallite size/lattice strain and crystallinity calculations, retained austenite quantification and polymorph screening (XRPD).

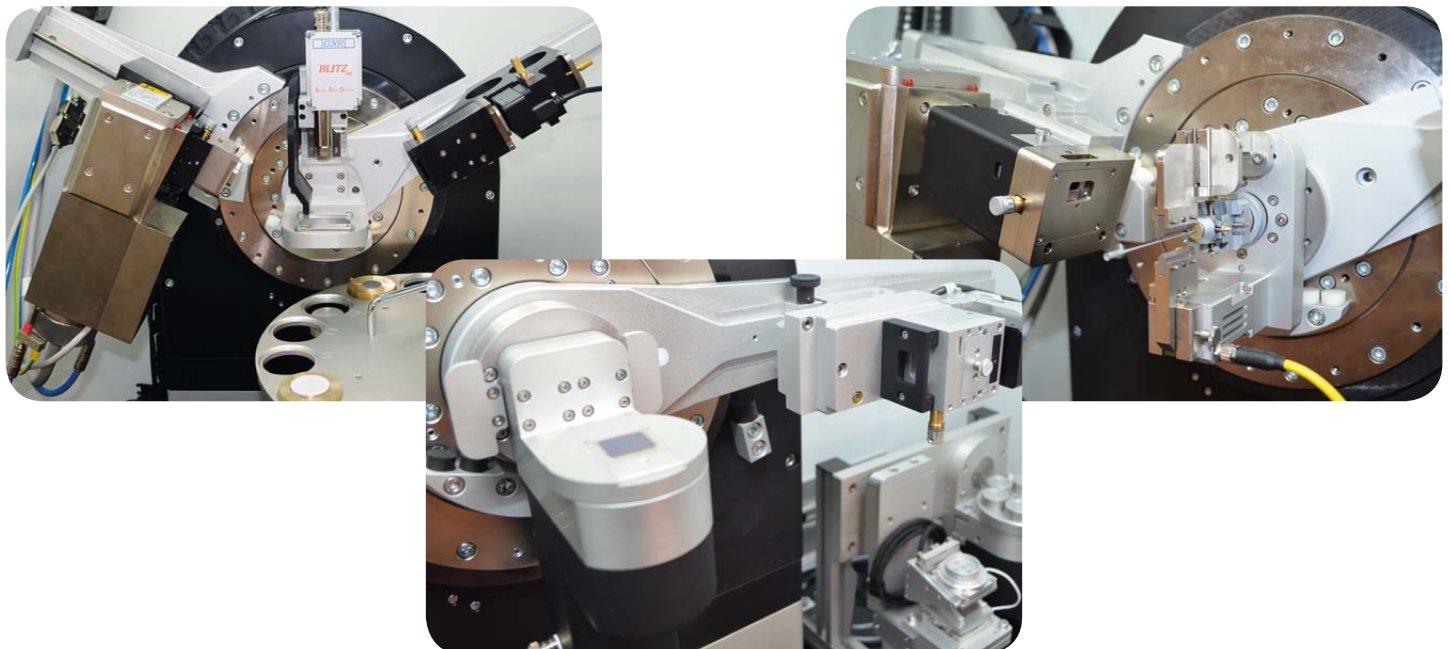
From crystal structures to residual-stress analysis, thin films (XRR, GID), non-ambient analyses, phase transition monitoring, textures and preferred orientation.

The coupling between a parabolic mirror monochromator and a channel-cut crystal mounted on the incident beam allows to realise a monochromatic parallel beam with high intensity and low divergence, suitable for high resolution measurements.

Each instrument always complies with the world's highest statutory requirements regarding X-ray, machine and electrical safety. Two independent, fail-safe safety circuits with separate shutter and "X-ray On" monitoring guarantee that the most recent radiation and personnel safety regulations are observed.

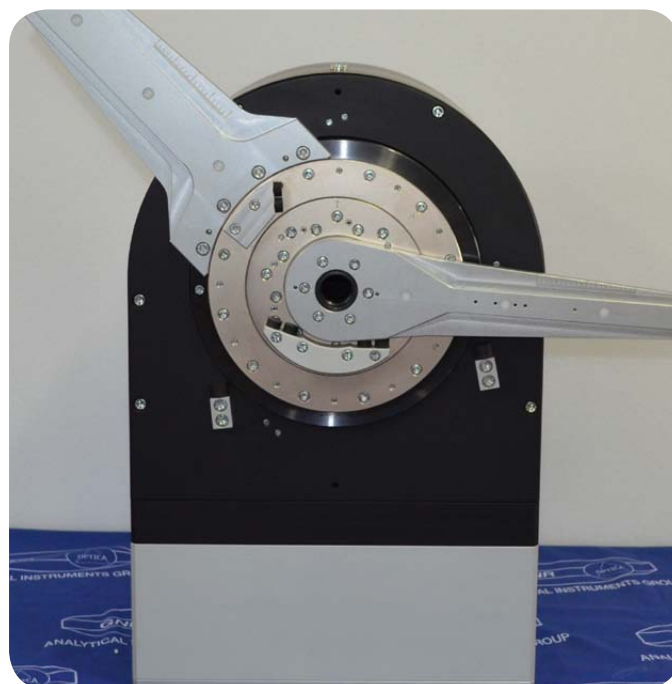
Main Features

- Goniometer control with torque motors and optical encoders
- Radiation enclosure with high accessibility to the goniometer
- Double safety circuits
- Three predefined measuring circle diameters: 400, 500, 600 mm
- All components can be exchanged quickly and without extra alignment
- High brilliant X-ray sources, glass and ceramic tubes plus parabolic mirror
- Rotatable line/point focus tube shield without disconnecting cables
- Interchangeable Soller slits
- Adjustable mechanical or motorized slits
- Reflection/transmission spinner
- Capillary spinner sample holder
- Reflection/transmission multisample holders
- Johansson focusing K-alpha₁ monochromators
- Secondary graphite monochromators
- Non-ambient experiments in reflection and transmission geometry
- High, low temperature and humidity chambers, fully software integrated
- Parallel beam optics using parabolic monochromators
- XRR and GID with incident and diffracted parallel beam
- HRXRD with 4-bounce channel-cut Ge monochromators
- SDD detectors for EDXRF and TXRF analysis
- SAXS analysis with transmission sample holder and fast multi strip 1D, 2D detectors
- Scintillation counters, silicon drift detectors (SDD), multi strip linear and area detectors (1D, 2D)
- Celerix multi strip linear detectors in 0D-mode and tilted by 90°
- Monocapillary and polycapillary collimators for high speed and high intensity texture analysis
- Z – Rx/Ry – Phi multipurpose sample holder
- Compact Eulerian Cradle for both iso (omega) and side (psi) inclination modes
- Versatile compact XYZ stage piezo motors



The Theta/Theta configuration allows easy sample preparation, as the measured surface remains in a horizontal plane while the tube and the detector arms are rotating. This configuration is equally suitable for the analysis of loose powders, liquids, thin films and heavy samples that cannot be easily fixed in position.

The **GNR Explorer** Theta/Theta high resolution diffractometer incorporates the high efficiency of the direct drive torque motors controlled by optical encoders, allowing to reach an angular accuracy of **0.00001°**.



Ultra-high-precision goniometer

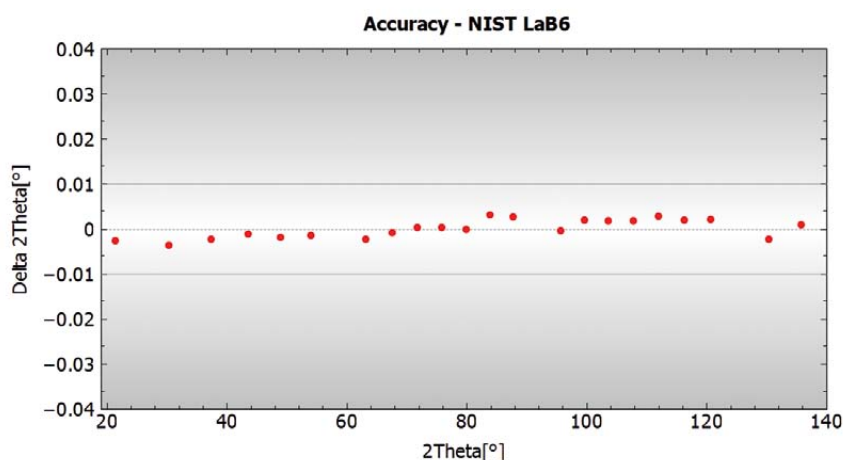


The direct drive technology offers many benefits compared with other well known technologies like worm gear, gear train, reducer or timing belt. The load is directly coupled to the motor rotating parts, resulting in an efficient and effective gearless construction.

GNR solid and maintenance-free goniometer is one of the key parameters to maintain this superior performance throughout the instrument lifetime.

You will be very impressed by our new **GNR Explorer** goniometer. **Torque motors with optical encoders** ensure extremely precise angular values.

Goniometer Accuracy



GNR developed a high performance goniometer featuring high precision and outstanding results.

An angular accuracy better than $\pm 0.01^\circ$ over the whole 2-Theta range guarantees optimal instrument alignment to support accurate and reliable analysis.

Every single instrument must pass internal test procedures based on the internationally accepted NIST Standard Reference Materials (SRM) Alumina 1976, Lanthanum Hexaboride 660 and Silicon Powder 640.

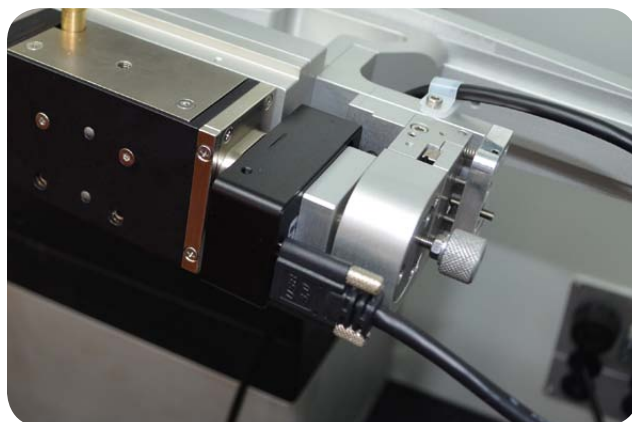
CeleriX 1D Hybrid Photon Counting (HPC) microstrip detectors

CeleriX multi strip detectors take full advantage of both Hybrid Photon Counting (HPC) and Single Photon Counting technologies, providing:

- X-Ray direct detection;
- noise-free performances;
- high intensity measurements;
- extremely fast data collection, without any sacrifice in data quality and peak resolution.

Our CeleriX 1D detectors allow to perform data collection in an extremely short time: they can capture simultaneously a large angular range and thus reducing measurement time from hours into minutes.

CeleriX 1D detectors can be used in 0D-mode and turned by 90° to cover an extremely large dynamic range.



CeleriX 1D mod. Advanced

Main Specifications	CeleriX 1D mod. Advanced	CeleriX 1D mod. Plus
Number of counting pixels	640	1280
Pixel width [μm]	50	50
Active area	256 mm ²	512 mm ²
Dynamic count rate range [counts/s]	Up to 1×10^{10}	Up to 1×10^{10}
Energy range [keV]	5-40	5-40
Cooling	Air	Air

Blitz - Silicon Drift Detectors (SDDs)

GNR Silicon Drift Detectors (SDDs) combine a large sensitive area with a small value of the output capacitance and are therefore well suited for high resolution, high count rate X-ray spectroscopy like EDXRF and TXRF.

Main Specifications	Silicon Drift Detector - SDD
Active area	5 – 100 mm ²
Shaping time	Standard: 1 μs or 250 ns
	Customizable: 10 μs - 100 ns
Energy resolution	Shaping time 1 μs : 124 eV FWHM@Mn K α
	Shaping time 250 ns: 136 eV FWHM@Mn K α
Cooling	Air



Blitz - Silicon Drift Detectors

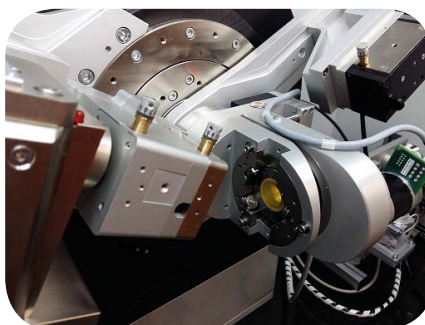
Capillary and reflection / transmission spinner sample holders

Both sample holders can be used with almost all types of samples: powder, suspensions, small sample quantities, air sensitive samples.

The transmission setup is the most appropriate choice for preferred orientation, organic materials with low absorption coefficients, sensitive sample measurements and Small Angle X-Ray Scattering (SAXS).

Very small sample amount or air-sensitive materials can be prepared in glass capillaries and measured by a high intensity beam with the advantage that all the crystallites of the rotating sample contribute to the diffraction signal.

Thanks to the primary parabolic mirror and the CeleriX multi strip detectors **GNR Explorer** produces high-quality data in an extremely short time, even with small samples quantities.



Reflection / transmission
spinner sample holder



Capillary sample holder

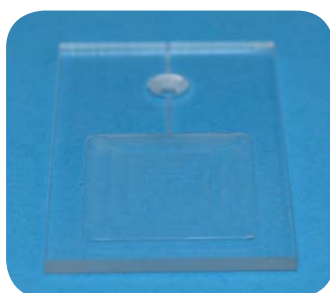
Specimen holders

GNR provides several dedicated solutions for different kinds of specimen. These fit to the analytical requirements and guarantee the best achievable data quality. Here below an overview of some specimen holders available. Upon request tailored solutions can be realized to further optimize the analytical results.

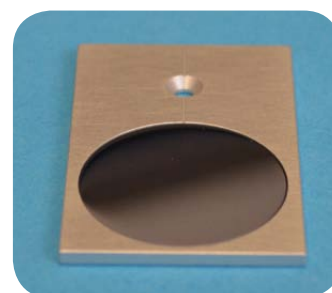
Flat specimen holders (length 44 mm)



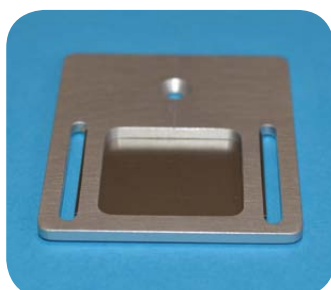
Front loading sample holder
Material: Al
Cavity:
HxL: 20 mm x 20 mm
Depth: 1 mm



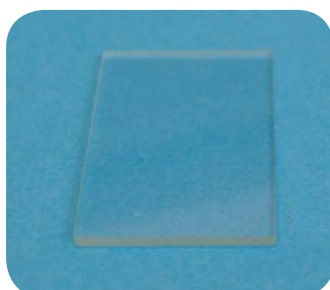
Front loading sample holder
Material: PMMA
Cavity:
HxL: 20 mm x 20 mm
Depth: 0.2/0.5 mm



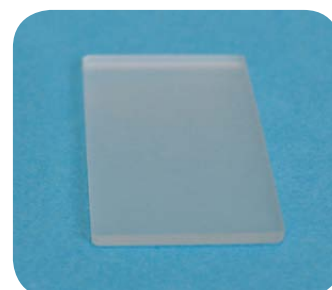
Si zero background sample holder
Material: Al
Cavity:
Diameter: 24.7 mm
Depth: 0.5/0.1 mm



Back loading sample holder
Material: Al
Cavity:
HxL: 20 mm x 20 mm
Depth: 1.9 mm



Glass slide for clay oriented mount

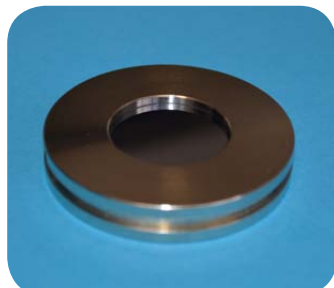


Glass slide for side loading sample
holder filling

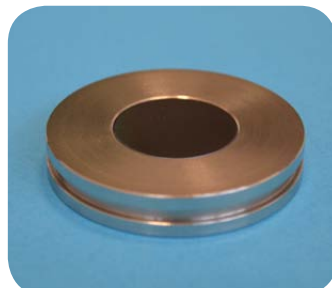
Circular sample holders (external diam: 51.5 mm - Herzog press)



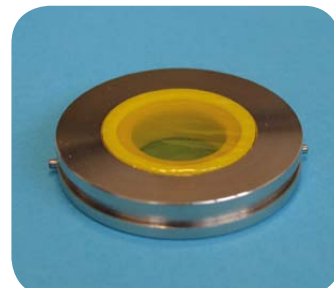
Back loading sample holder
Material: steel
Cavity:
Diameter: 24.7 mm
Depth: 2.5 mm



Side loading sample holder
Material: steel
Cavity:
Diameter: 24.7 mm
Depth: 2 mm

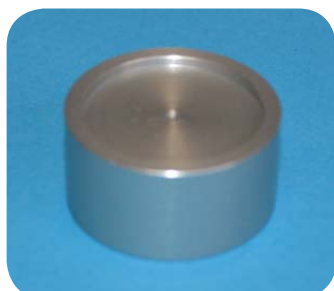


Si zero background sample holder
Material: steel
Cavity:
Diameter: 24.7 mm
Depth: 0.2 mm



Reflection/transmission sample holder with X-Ray transparent film for air sensitive samples
Material: steel
Sample volume:
Diameter: 20 mm
Thickness: 0.5/1 mm

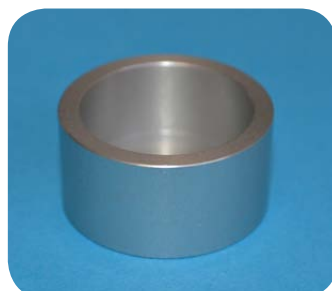
Circular sample holder for Z, Rx/Ry, Phi stage (diameter: 30 mm)



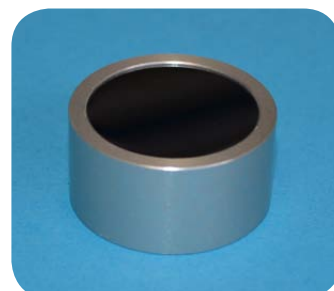
Powder sample holder
Material: Al
Cavity:
Diameter: 22/24.7 mm
Depth: 1/1.5/2 mm



Powder/Thin film sample holder
Material: PMMA
Cavity:
Diameter: 22 mm
Depth: 0.2/0.5/1 mm

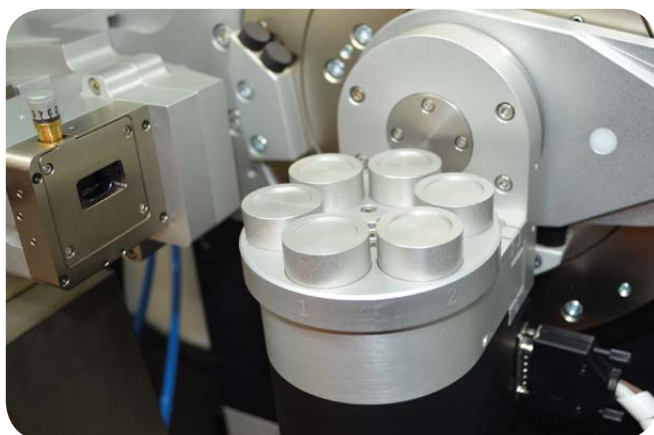


Massive sample holder
Material: Al/PMMA
Cavity:
Diameter: 24 mm
Depth: 12 mm

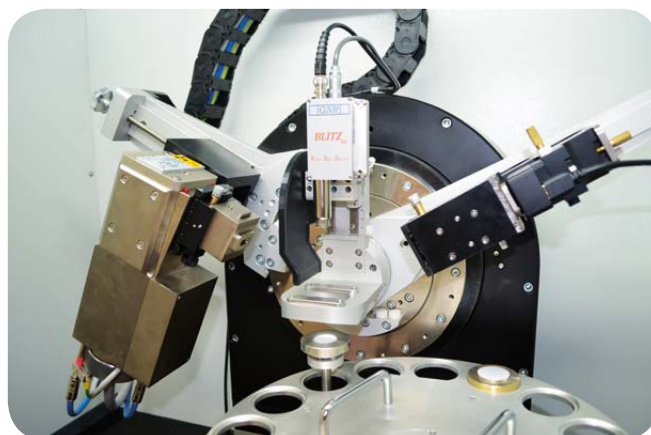


Si zero background sample holder
Material: Al
Cavity:
Diameter: 24.7 mm
Depth: 0.5 mm

Multi sample holders



6-position auto-changer



15-position auto-changer (ext. diam: 51.5 mm)

GNR multi sample stages can be used both in reflection and transmission mode in order to meet customer requirements and to analyse almost every kind of samples.

Non-ambient X-ray diffraction has become an indispensable technique to understand the influence of temperature, atmosphere or pressure on materials of any kind. Besides its relevance for conducting research, this knowledge is essential for optimizing technical processes and performing quality control in industrial applications.

Automatic sample height compensation also guarantees the correct geometrical position of the sample in the X-ray beam throughout the experiment. Use of high-quality materials avoids unwanted chemical reactions between sample and stage components and ensures a long lifetime for the equipment.

HTK 16N / HTK 2000N - Filament heating up to 2300 °C

Technical data	
Temperature range	25 °C to 1600 °C (HTK 16N)
	25 °C to 2300 °C (HTK 2000N)
Atmospheres	Air/inert gas, up to 1600 °C
	Vacuum (10^{-4} mbar), up to 2300 °C
X-ray geometry	Reflection



HTK 16N / HTK 2000N

Environmental heating for homogeneous sample temperature - HTK 1200 / HTK 1200 Capillary

Technical data	
Temperature range	25 °C to 1200 °C
Atmospheres	Air, inert gas, vacuum (10^{-4} mbar)
X-ray geometry	Reflection and transmission



HTK 1200 / HTK 1200 capillary

Low-temperature XRD studies between -190 °C and 600 °C - TTK 600

Technical data	
Temperature range	-190 °C to 600 °C (liquid-nitrogen cooling)
	-10 °C to 600 °C (compressed-air cooling)
Atmospheres	Air, inert gas, vacuum (10^{-2} mbar)
X-ray geometry	Reflection and transmission



TTK 600

Studies under controlled temperature and relative humidity conditions - CHC plus+

Technical data	
Temperature range	-180 °C to 400 °C (vacuum)
	-120 °C to 300 °C (dry air)
RH range	5 to 95% RH from 10 °C to 60 °C
	5 to 70% RH at 80 °C
Atmospheres	(Humid) air, inert gas, nitrogen, vacuum (10^{-2} mbar)
X-ray geometry	Reflection



CHC plus+

EXPLORER

X-RAY POWDER DIFFRACTION (BRAGG-BRENTANO) CONFIGURATION

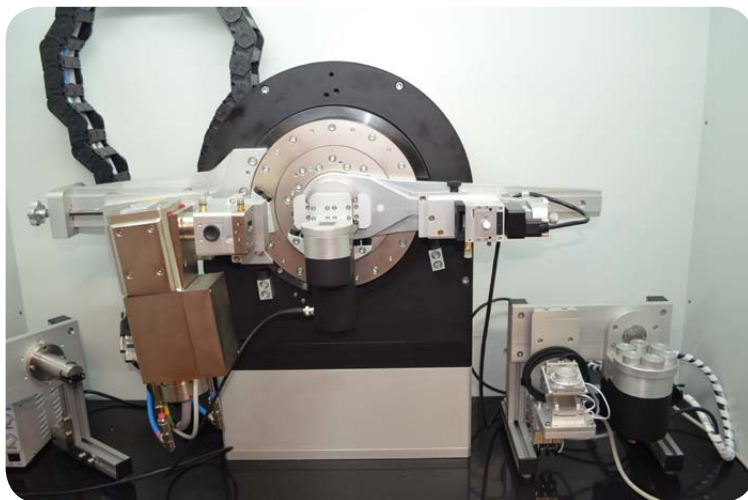
Phase analysis is the study of the different polycrystalline materials within a sample. One phase is identified among the others due to its unique powder diffraction pattern which arises from its unique combination of composition and crystal structure.

The analysis is applicable to all types of crystalline materials and can be restricted to identification only or extended to full quantitative analysis.

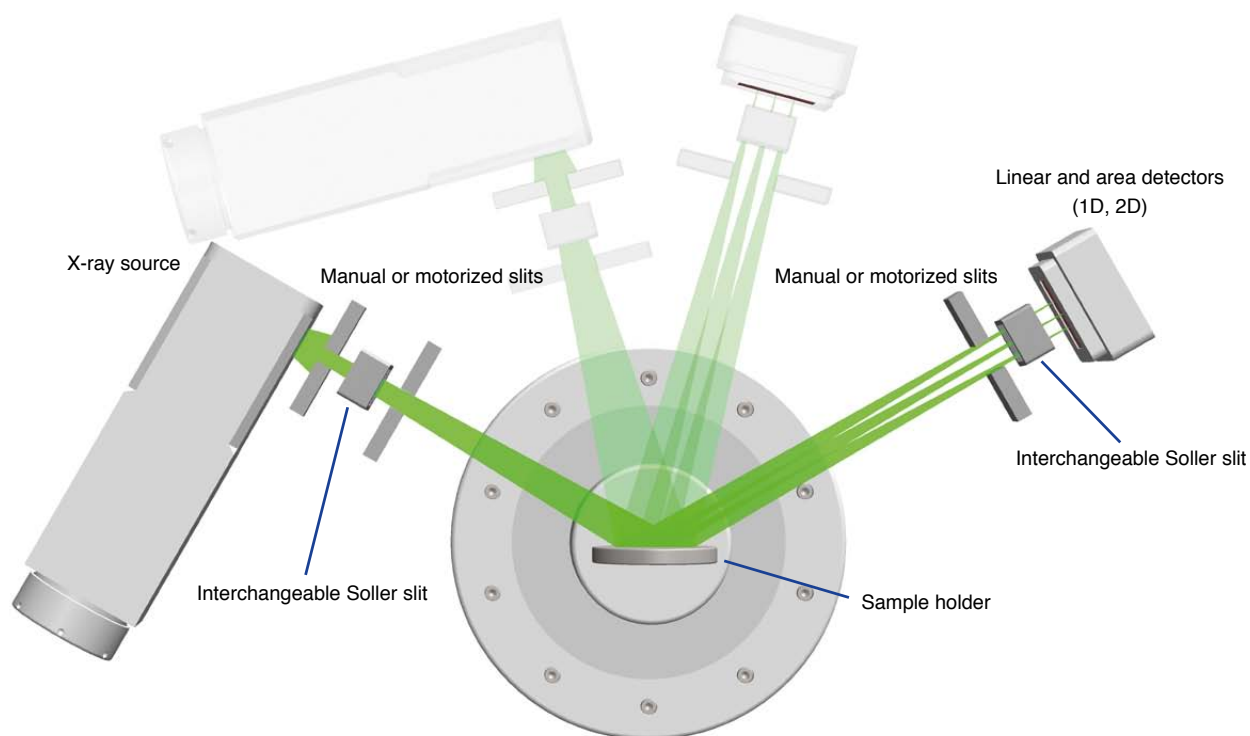
Mounting a capillary spinner and a multi strip linear detector, **GNR Explorer** is ready to accept powder samples prepared in glass capillaries. This option is useful for material that may be sensitive to oxidation or humidity.

With a polycapillary accessory on the incident beam plus the suitable sample stage, a spot of 0.1 mm makes it possible to carry out microdiffraction measurements on small samples such as forensic specimens. The development in manufacturing polycapillary optics is directed to a further decrease of focal spot size and an increase of brilliance.

Powders with complex crystallographic structures are measured with $K\text{-}\alpha_1$ radiation produced by a Johansson monochromator, which allows to have clearer powder diffractograms by removing $K\text{-}\alpha_2$ contribution. It is ideal for crystallographic analyses such as cell searching, indexing, unit cell refinement and structure solution from powder data.



Bragg-Brentano geometry

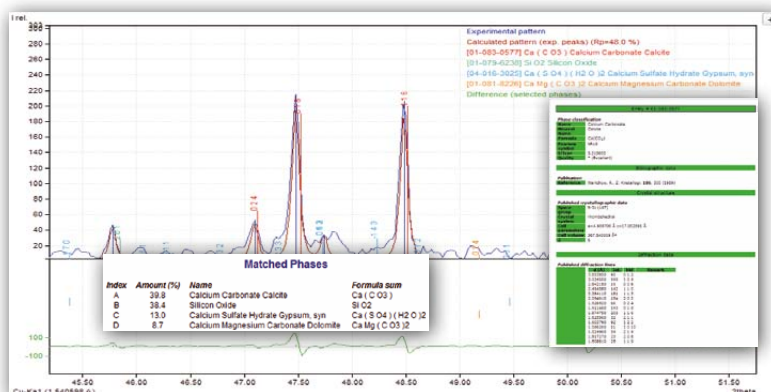


EXPLORE POWDERS

- Crystalline phases ratio (E. Calibration, RIR, Rietveld)
- Amorphous content in samples
- Crystal structure
- Phase transitions
- Crystallinity index and percentage

Phase Identification and Quantitative - Mineralogy

GNR Explorer can be used in phase identification and quantitative analysis in mineralogy domain. Match! can identify the phases present in the sample and report the weight percent composition. In this case the sample is a mixture of Quartz, Calcite, Gypsum and Dolomite.

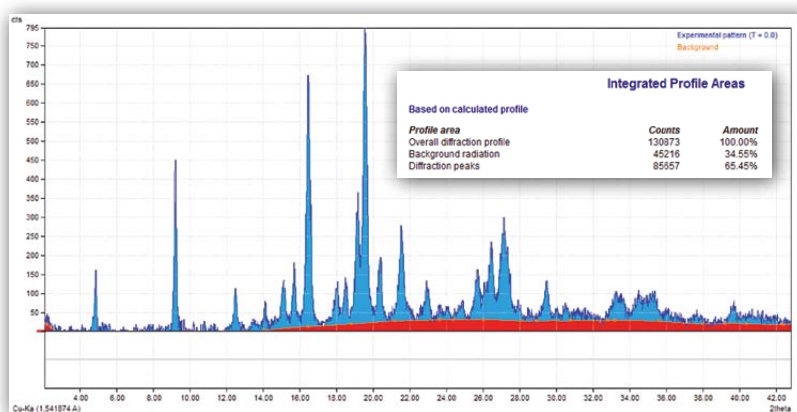


Quantitative Phase Analysis using Match!

Crystallinity Degree Calculation - Pharmaceutical

In pharma industry product development and quality assurance it is common to measure the amorphous phase amount in order to determine the degree of crystallinity.

It is important to monitor the amount of the amorphous phase within a drug because of its thermodynamic instability, relative to the crystalline state. Match! allows to determine it easily through the Degree of Crystallinity calculation.

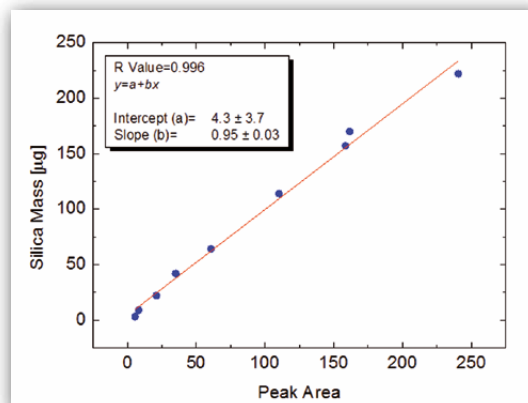
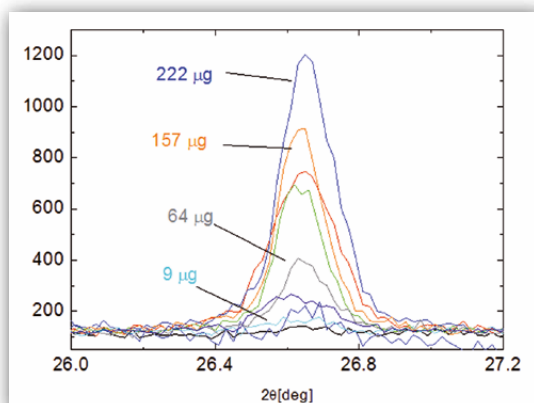


Crystallinity Degree Calculation using Match!

Silica Dust Monitoring - Environmental

Crystalline silica is a basic component of soil, sand, granite, and many other minerals. Quartz is the most common form of crystalline silica. The seriousness of the health hazards associated with silica exposure is demonstrated by the fatalities and disabling illnesses that continue to occur in sandblasters and rock drillers. Crystalline silica has been classified as a human lung carcinogen. Measuring and quantifying silica dust collected on air filter is important to protect health of workers involved in activity exposed to silica dust.

Quartz (101) diffraction peak area is proportional to the mass of silica dust deposited on a filter. Using NIST – SRM 1878 quartz standard is possible to calculate a calibration curve for silica dust mass quantification and monitoring.



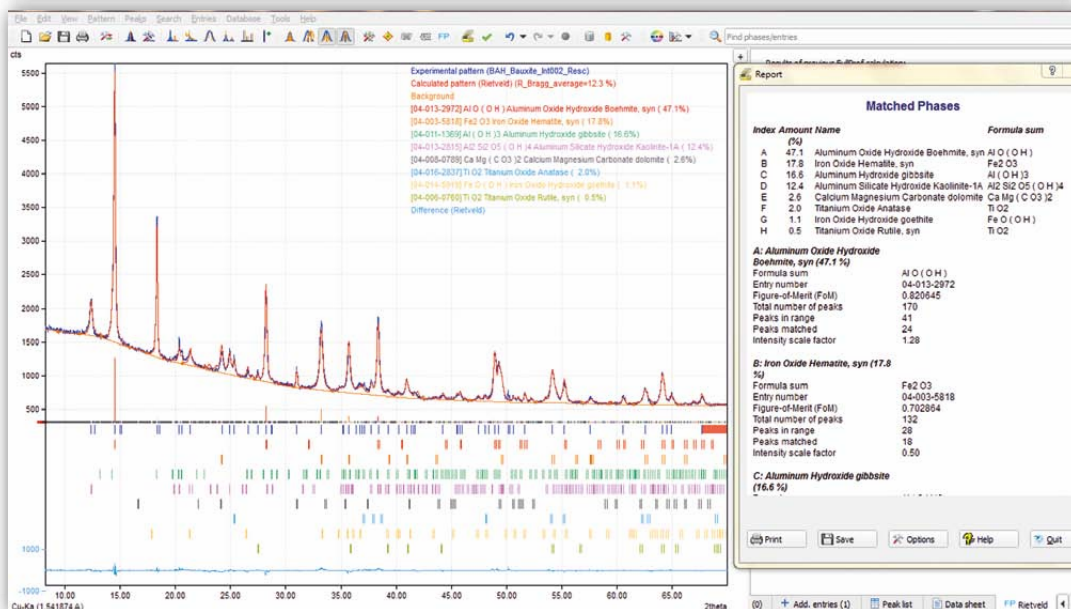
Calibration curve for silica dust mass quantification

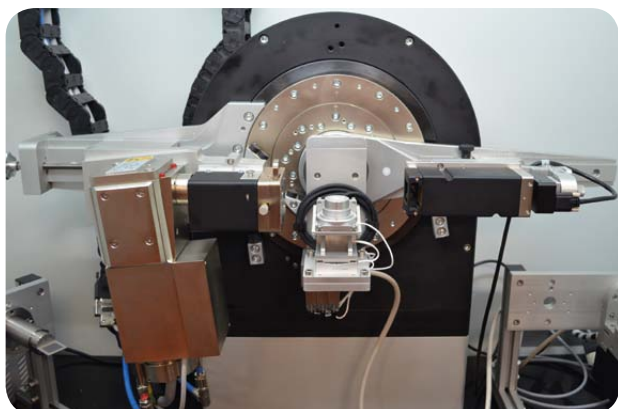
GNR software supports several type of analysis, from Data Acquisition, having the full control of all the process and hardware settings (motors, x-ray generator and tube, detector, measurement set up), to Data Analysis.

It compares the diffraction pattern of your sample to a database containing reference patterns in order to identify the phases present in the sample. Additional knowledge about the sample like known phases, chemical elements or density can be applied.

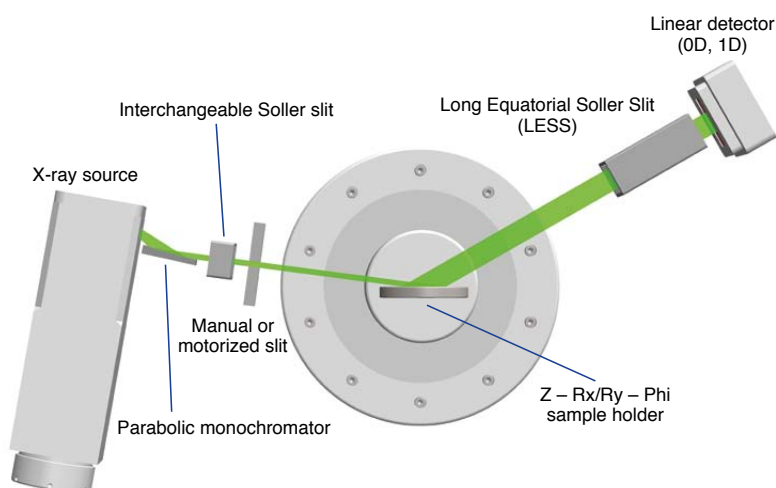
End user can easily setup and run Rietveld refinements within Match!, with the actual calculations being performed automatically, using the well-known program FullProf in the background. Match! provides a gentle introduction into Rietveld refinement, from fully automatic operation to the “Expert” mode.

As reference database, you can apply the included free-of-charge COD database and/or ICSD/Retrieve (if you have a valid license), use any ICDD PDF product, and/or create a user database based on your own diffraction patterns.





Parallel beam geometry



EXPLORE THIN FILMS

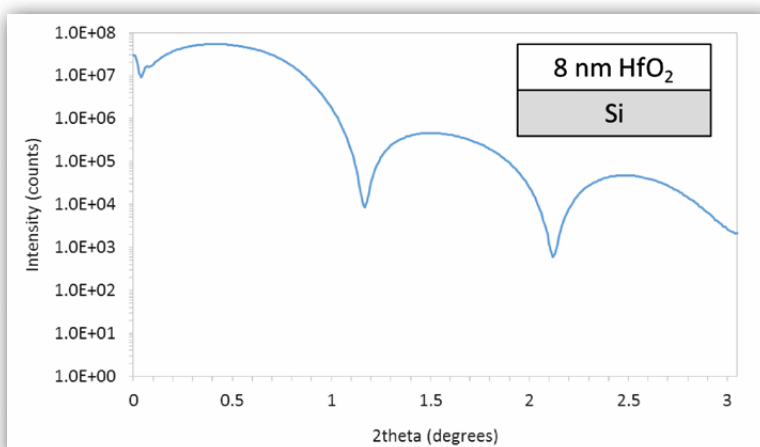
- Layer(s) phases
- Layer roughness
- Residual stress
- Layer thickness
- Layer density
- Micro-strains

Reflectometry (XRR)

The **GNR Explorer** can accomplish in a single measurement the characterisation of thin film layer thickness, density, surface and interface roughness. If the films are single or multilayer, only a few atoms or up to about 0.2 μm thick, the procedure is fast, easy and completely non destructive.

The specificity of our reflectometry configuration is based on the optimal combination of parabolic mirror, multipurpose piezoelectric sample stage, knife edge collimator and Celerix 1D detector.

The high resolution reflectometry studies can be performed with **GNR Explorer** to characterise layer thickness from 1 to 200 nm with an accuracy better than 1%, density with an accuracy better than $\pm 0.03 \text{ g/cm}^3$, surface and interface roughness from 0 to 5 nm with an accuracy better than $\pm 0.1 \text{ nm}$.

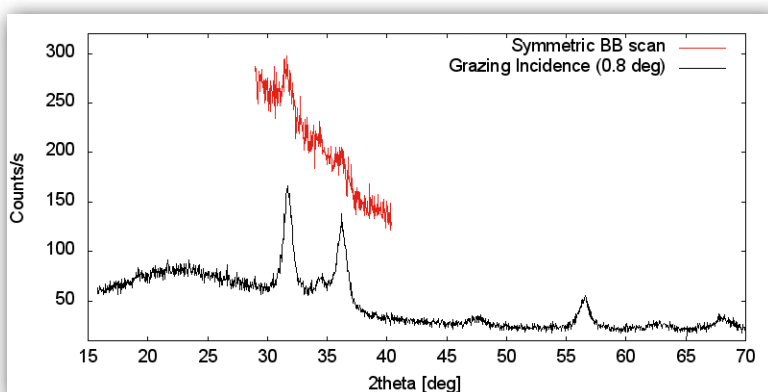


XRR - 8 nm of HfO_2 deposited on Si

Grazing Incidence Diffraction (GID)

Coatings and other thin polycrystalline layers can be measured at a fixed angle of incidence using parallel beam geometry.

Measurements can be done at low glancing angles of the X-ray beam to increase the intensity of the signal from the layers while reducing the substrate contribution. During the measurement the incidence angle remains fixed while the detector is scanned through the 2-theta range.



GID - comparison between traditional symmetric (Bragg Brentano) and grazing incidence geometry for ZnO thin film on glass substrate: the thin film signal is almost completely hidden by the glass substrate one in traditional Bragg Brentano geometry (red profile)

■ ■ ■ Parabolic mirror monochromator

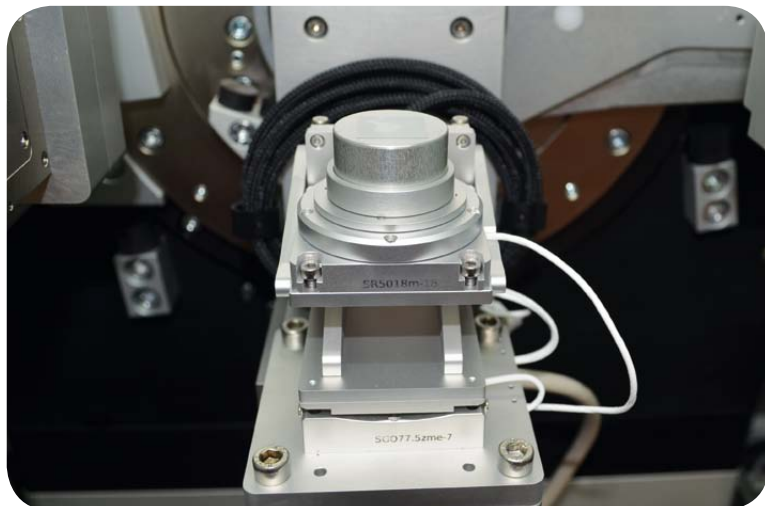
The parabolic mirror is a parabolic graded multilayer, whose purpose is to convert the divergent beam from the X-Ray tube anode into a parallel monochromatic beam in the equatorial plane. The parabolic monochromator provides additional performances for reflectivity measurements (XRR) and grazing incident diffraction (GID) with its high intensity beam.



Parabolic mirror monochromator

■ ■ ■ Z – Rx/Ry – Phi multipurpose sample holder

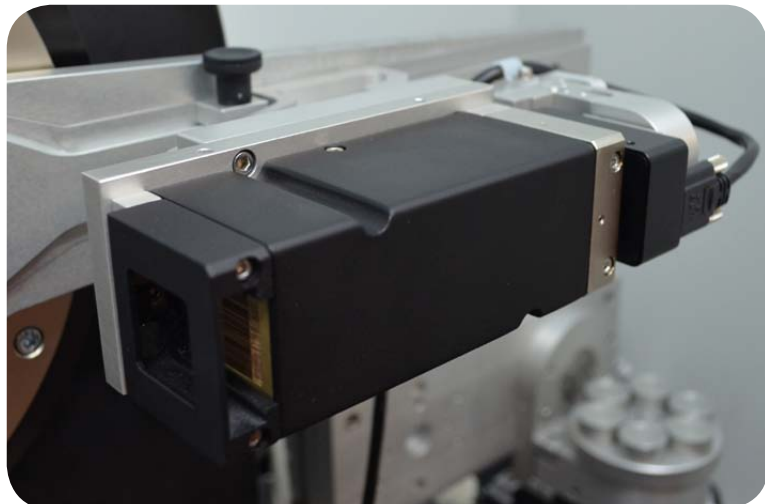
Motorized Z - Rx/Ry - Phi sample stage allows an easy and accurate sample alignment: this is very important when measuring coatings, thin films and small samples in general. Fast, accurate and software-controlled micro sample positioning, is achieved using piezoelectric motors.



Z – Rx/Ry – Phi multipurpose sample holder

■ ■ ■ Long Equatorial Soller Slit (LESS)

The Long Equatorial Soller Slit (LESS) consists of a set of parallel plates separated by equal spacers, which results in a set of narrow parallel collimators defining the equatorial acceptance angle seen by the detector. The LESS attachment is used in the Explorer diffractometer when polycrystalline samples in the form of thin film or multilayers have to be analysed with the grazing incidence geometry.



Long Equatorial Soller Slit (LESS)

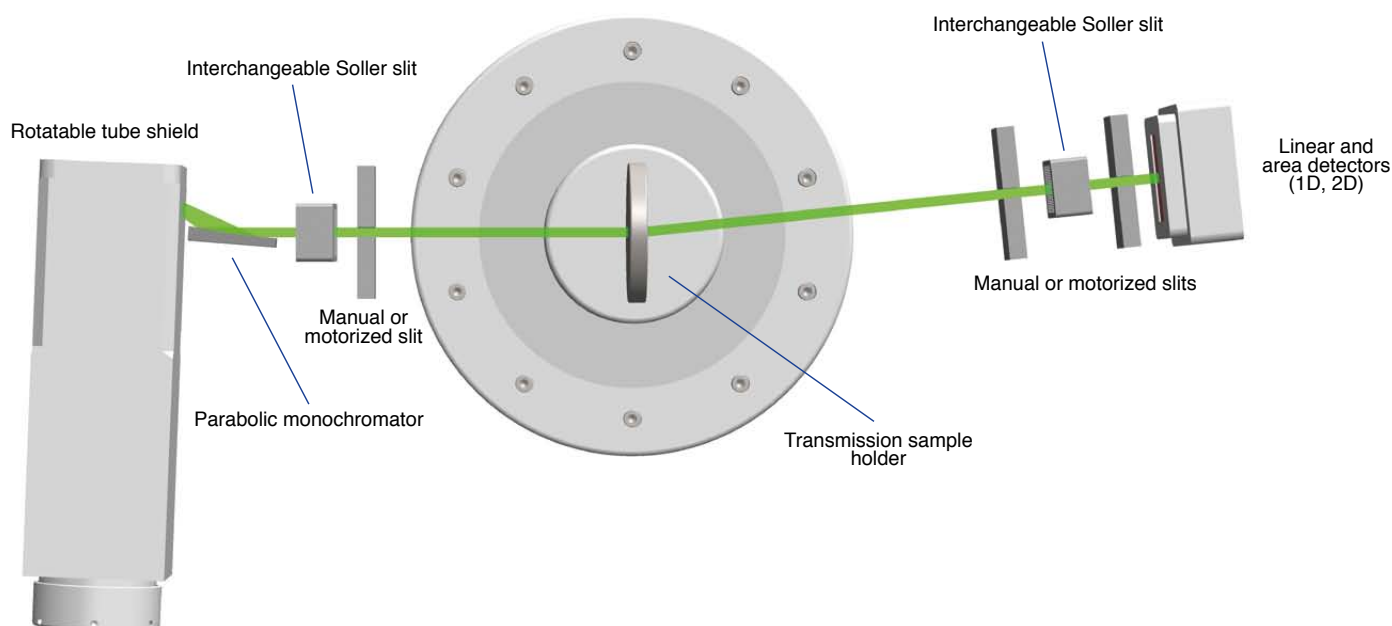
Small Angle X-Ray Scattering (SAXS) is an important tool in X-ray diffraction for the study of the structure of nanomaterials. SAXS applications include:

- Particle size distribution of nanoparticles suspended in solution
- Particle/pore size distribution in deposited or bulk solid nanomaterials
- Particle shape analysis
- Correlation function analysis of irregular electron density distribution

Setups for SAXS measurements require a narrow, highly collimated and intense X-ray beam, the effective suppression of any parasitic scattering, and a detector with a high linearity range.

The objective is to measure the scattered intensities in the immediate vicinity of the direct beam, typically down to 0.1 deg and below. The smallest accessible scattering angle determines the upper limit of the dimension (e.g. particle diameter) that can be analysed.

Particle from 1 to 100 nm in size can be studied using **GNR Explorer** in SAXS configuration.



EXPLORE NANO-POWDERS

- Crystallite size
- Particle size distribution
- Pore size
- Crystallinity

GNR Explorer benefits from the latest developments in detector technology and high-flux microfocus X-ray sources, fulfilling the needs for precision, speed and reliability.

GNR Explorer performs at the best SAXS analysis with high brilliance mono and polycapillary collimators, the transmission sample holder and the fast multi strip 1D, 2D detectors.

RESIDUAL STRESS AND TEXTURE CONFIGURATION

Some macroscopic features of metals, minerals, ceramics and polymers are related to the microscopic properties (microstructure) like crystal lattice strains (residual stress) or preferred orientations (texture).

Microstructural investigations are effectively performed by X-ray diffraction to control production processes.

Residual stress and texture analyses require measurements with several orientations of the sample in order to obtain the complete stress and texture conditions.

With our compact and high precision Eulerian Cradle we can rotate, incline and adjust our sample (Φ , χ , Z) under software control with several data collections and evaluation strategies.

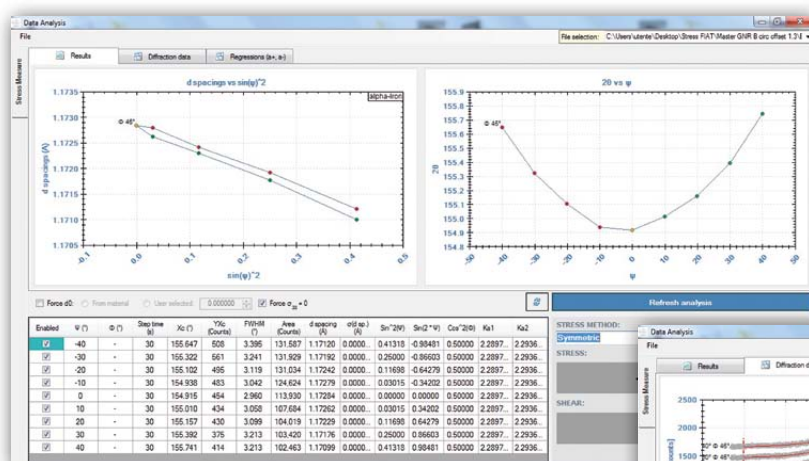
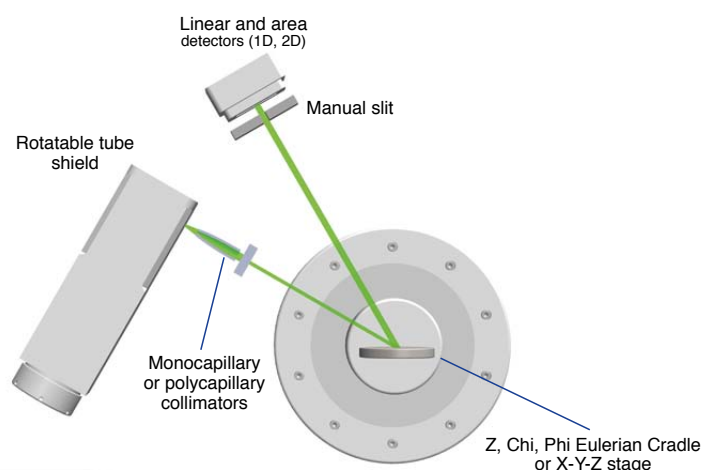
Recent development in high brilliance optics and fast detectors offer result in enhanced quality and reduced time consumption.

If need higher intensity at only one specific point and a high resolution with maximum speed, our polycapillary lenses together with the Celerix 2D detectors are the best choice.

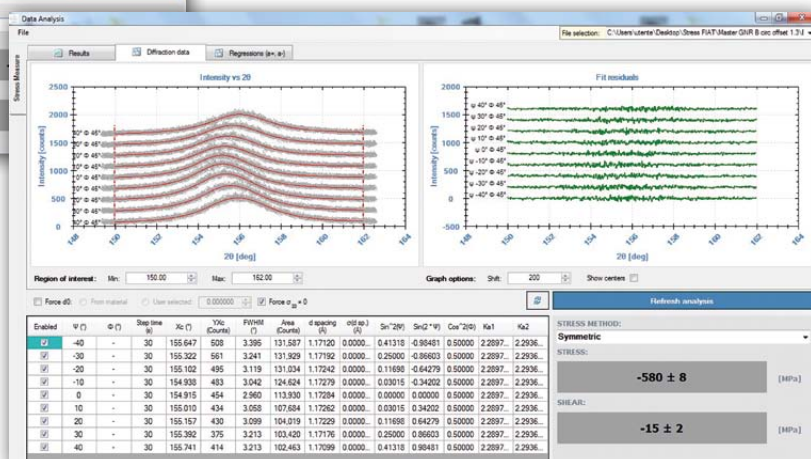
The 2D detectors offer the possibility to simultaneously detect the diffracted beam intensities of a large Chi and 2-Theta angle with little or no sample or detector movement.



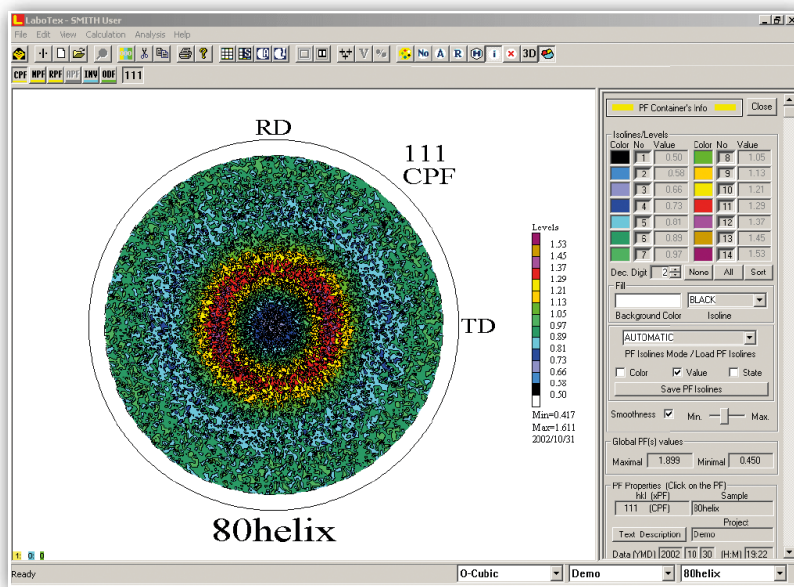
Residual stress and texture geometry



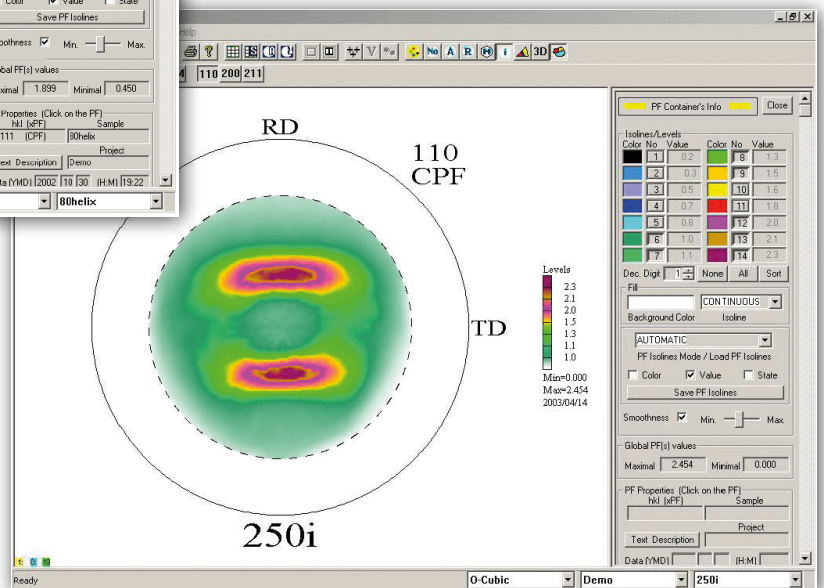
Stress Analysis panel: results tab



Stress Analysis panel: diffraction data tab



ODF calculation from Pole Figures



Qualitative and quantitative texture analysis

Rotatable tube shield

The majority of powder diffraction measurements on polycrystalline materials are done with line focus. For stress and texture measurements, point focus is more suitable. Hence, an easy switching from line to point focus is an important feature of a true multi-purpose diffractometer.



EXPLORE MICROSTRUCTURE

- Micro-strain
- Crystallographic textures (ODF, PFs, IPFs)
- Stress tensor
- Compressibility
- Deformation
- Qualitative and quantitative texture analysis

GNR Explorer in shielded glove box



GNR Explorer in shielded glove box

Radioactive materials can be characterized for chemical form and certain physical properties with **GNR Explorer** customized for containment in a shielded glove box. The glove box has several special engineered features for nuclear and X-ray safety. The facility is designed to handle alpha and beta emitting samples with moderate neutron and gamma radiation.

Samples containing plutonium and other transuranic elements can be analysed to support nuclear site, waste handling and waste stabilization operations.

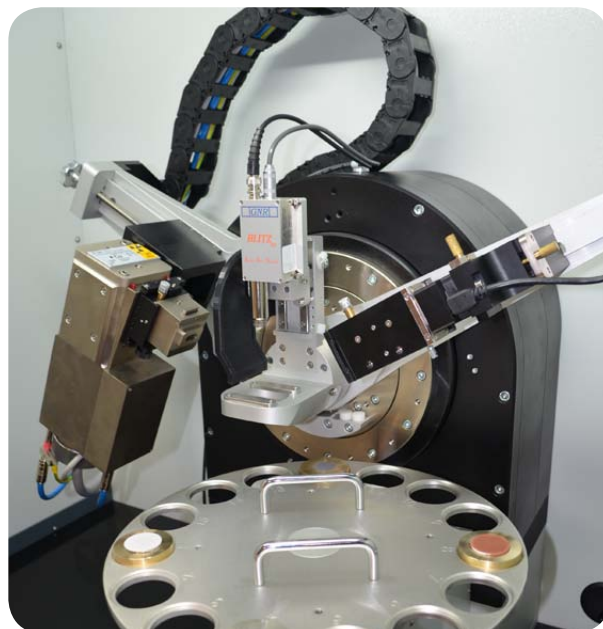
Aluminum electrolytic bath monitoring by GNR Explorer

The optimization of aluminum production process by electrolytic reduction requires constant monitoring of the bath parameters: X-ray diffraction has been an effective technique to determine Bath Ratio and Excess AlF_3 for several years.

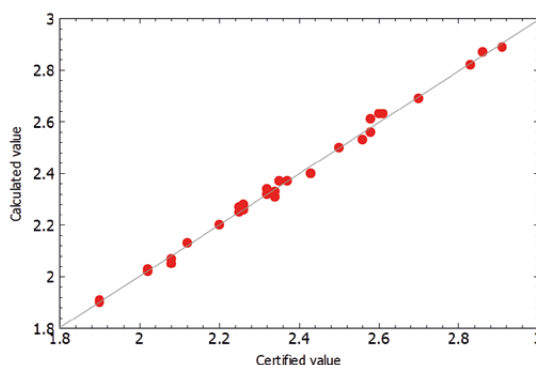
The **GNR Explorer** with CeleriX 1D detector, Blitz SDD detector and 15-position auto-changer allows to cope with short available time for measurement and analysis in an easy-to-use way.

Besides, the use of a Silicon Drift Detector for XRF allows to monitor the content of both Ca and other elements of interest (e.g. K) at the same time, which can be very useful for an unconventional bath chemistry.

GNR Explorer in aluminum electrolytic bath configuration allows to determine electrolytic bath parameters (BR, CR, ExAlF_3) in a fast and easy way. Reference samples have been used to set-up calibration curves that are adopted in the analysis. User loads real production samples and analysis the results. Successful testing was performed with both Alcan Electrolytic Bath standards and custom-reference standards.

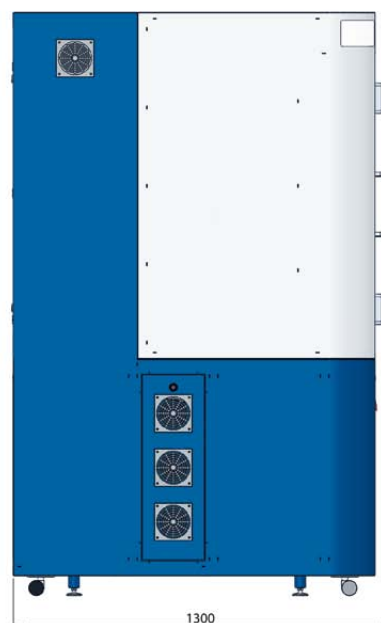


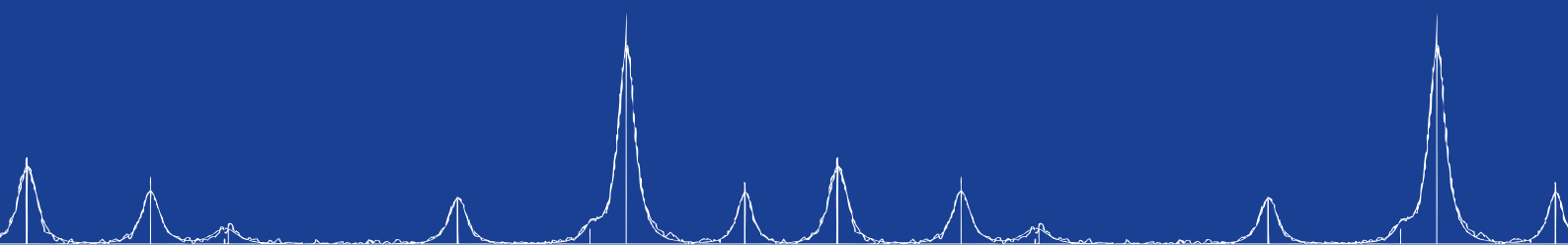
GNR Explorer in aluminum electrolytic bath configuration



CR calibration curve with customer standards
RSD=0.02

Configurations	Vertical Theta/2Theta and Theta/Theta geometry
Measuring circle diameters	400 - 500 - 600 mm or any intermediate setting
Scanning angular range	- 110° < 2 theta < + 168° (depends on accessories)
Angle positioning	Direct drive torque motors with optical encoders
Smallest selectable stepsize	0.0001°
Angular accuracy	Better than ± 0.01° over the whole 2-Theta range
X-ray generator	3 kW (option 4 kW)
Max. output voltage	60 kV
Max. output current	60 mA (option 80 mA)
Voltage step width	0.1 kV
Current step width	0.1 mA
X-ray tube	Glass (option ceramic), Cu anode (option: Co, Fe, Cr, Mo, W, Ag)
Focus	0.4x12 mm LFF (Long Fine Focus) (options: 0.4x8 mm FF; 1x10 mm NF; 2x12 mm BF)
Detectors	Scintillation counter Celerix 1D/2D multi strip detectors Silicon Drift Detectors (SDDs)
External dimensions	Width 1450 mm, height 1980 mm, depth 1300 mm
Weight	605 Kg
Cooling water supply (without optional water chiller)	Min. flow rate: 4l/min – Pressure 4 bar to 6 bar
Maximum power consumption (including water chiller)	10 kVA





Local Agent



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